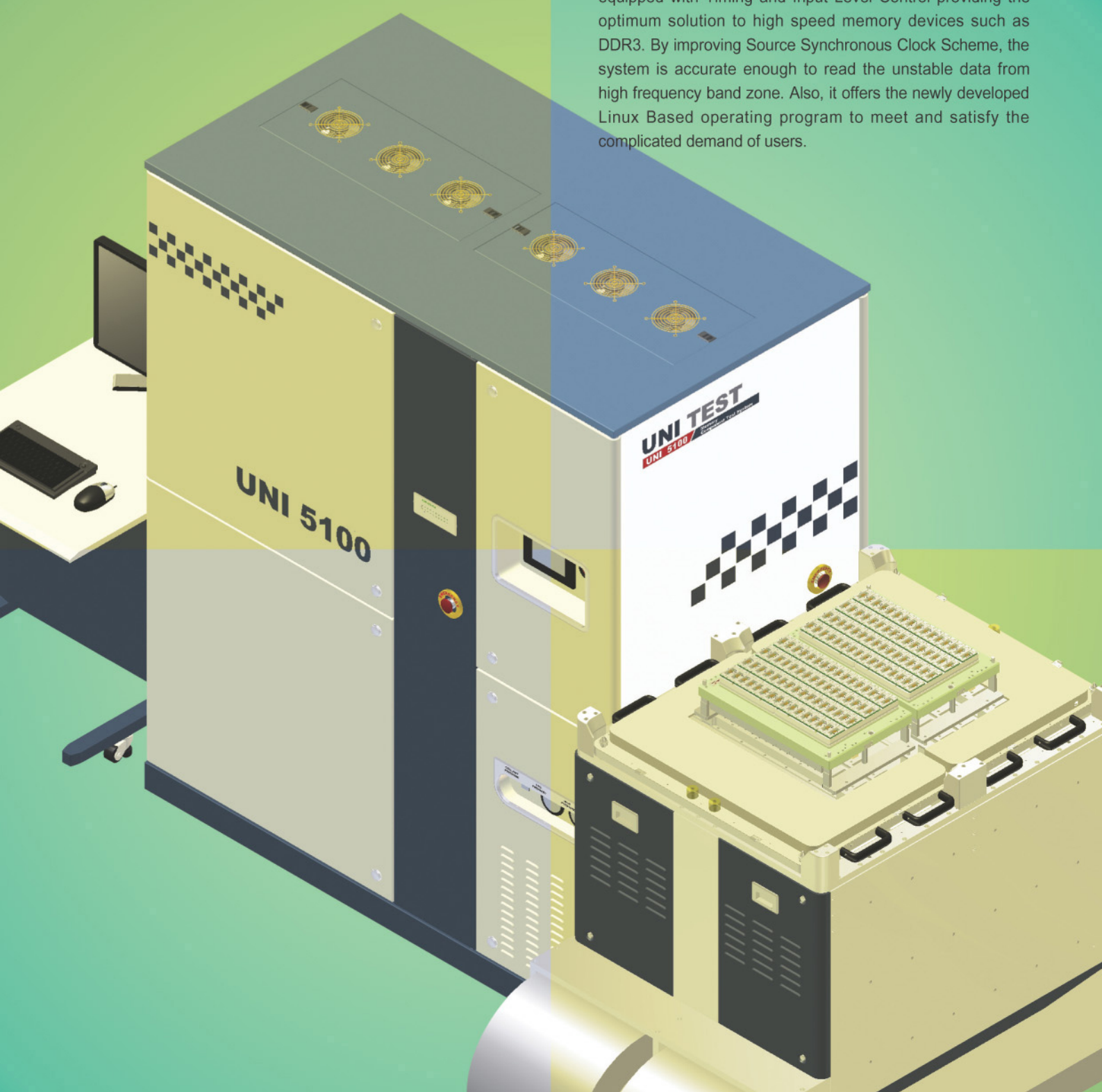


UNI 5100

UNI5100, the high performance Memory Test System, is equipped with Timing and Input Level Control providing the optimum solution to high speed memory devices such as DDR3. By improving Source Synchronous Clock Scheme, the system is accurate enough to read the unstable data from high frequency band zone. Also, it offers the newly developed Linux Based operating program to meet and satisfy the complicated demand of users.



Providing Optimum Solution for testing
High Speed Memory Devices such as DDR3.

UNI 5100



Memory Types Supported	DDR2, 3 SDRAM & GDDR SDRAM
Test Frequency	Up to 600MHz[1.2Gbps]
Parallel Test	256 DUTs/system
ALPG	Real time Algorithmic Pattern Generator
Test Pattern	Programmable
Analysis Tool	Fail Bitmap, Shmoo Plot
Automated System [optional]	Vertical or Horizontal Memory Handler
Handler Interface	GPIB

** Specifications may be changed without notification.*